Search Notes	earch Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/816,696	LAM, AN HIEN
Examiner	Art Unit
Biju Chandran	2835

	SEARCHED			
Class	Subclass	Date	Examiner	
361	676	11/21/2005	віС	
361	678	11/21/2005	BIC	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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